	Sunday, May 22
8:00	**Tutorials Registration at TUT**
9:00	**Tutorials 1 & 2 at TUT**
12:00	**Lunch**
13:00	**Tutorials 1 & 2 at TUT**
16:00	**Symposium Registration**
19:00	**Reception at the Historic Tallinn Town Hall**

	Monday, May 23	
7:30	**Symposium Registration**	
8:30	**Opening Session** *Academic Keynote* *Industrial Keynote*	
10:00	**PhD Forum**	**Poster Session 1**
11:00	**Session 2.a:** SOC Testing	**Session 2.b:** Advances in Fault and Defect Model
12:30	**Lunch**	
14:00	**Session 3.a:** Advanced Test Generation Issues	**Session 3.b:** On-line and BIST Techniques for MEMS
15:30	**Poster Session 2**	
16:30	**Session 4.a:** Low Cost Testing for Advanced Analog Circuits	**Session 4.b:** Effective Test Generation and Optimization
18:00		
19:00	**Dinner**	
20:30	**Evening Panels**	
22:00		

	Tuesday, May 24	
8:30	**Session 5.a:** Defect and Dynamic Fault Testing	**Session 5.b:** SRAM Memory Testing
10:00	**Poster Session 3**	
11:00	**Session 6.a:** Testing Regular Structures	**Session 6.b:** Advances in Characterization and Diagnosis
12:30	**Lunch**	
14:00	**Session 7.a:** Embedded Tutorial 1	**Session 7.b:** Embedded Tutorial 2
15:00		
15:30	**Social Event**	

	Wednesday, May 25	
8:30	**Session 8.a:** Validation & Molecular Electronics	**Vendor Session 8.b**
10:00	**Poster Session 4**	
11:00	**Session 9.a:** Fault Diagnosis and Memory Test	**Session 9.b:** Dedicated Test Resources
12:30	**Lunch**	
14:00	**Session 10.a:** Embedded Tutorial 3	**Session 10.b:** Embedded Tutorial 4
15:00	**Session 11:** SOC Testing & Secure IC	
16:30	**Closing Session**	